

S/N Unknown

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Gary R. Gilliam

Examiner: Unknown

Serial No.: Unknown

Group Art Unit: Unknown

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Title: ON-CHIP SUBSTRATE REGULATOR TEST MODE

PRELIMINARY AMENDMENT

BOX PATENT APPLICATION

Commissioner for Patents

Washington, D.C. 20231

*a / Prel. amdt.*

*A*

*E. Gillis*

*11-21-01*

Sir:

When the above-identified patent application is taken up for consideration, please amend the application as follows:

IN THE SPECIFICATION

On page 1, line 3, before the heading "Field of the Invention," insert the following paragraph:

Cross Reference to Related Application(s)

This application is a division of U.S. Application No. 09/065,139, filed on April 23, 1998, which is a division of U.S. Application No. 08/520,818, filed on August 30, 1995, now issued as U.S. Patent No. 5,880,593, the specifications of which are hereby incorporated by reference.

Please substitute the following paragraphs of the Specification with the paragraphs in the appendix entitled "Clean Version of Specification Paragraphs." Following are marked-up versions of the amended paragraphs showing specific changes:

The paragraph beginning on page 4, line 19, is amended as follows:

For example, in Figure 1, the non-test condition of EN1 may be at a logical [los] low so that the MOSFET M3 is in the diode chain because the MOSFET M4 is off. The non-test condition of EN2 may be at a logical high so that the MOSFET M5 is essentially shorted out of the diode chain because the MOSFET M6 is on. Therefore, the voltage level of the substrate at node Vbb, under non-test conditions, is substantially equivalent to the supply voltage level Vcc, less the voltage dropped by the three MOSFETs M1, M2 and M3. Under test conditions, the